(ii) the DSC thermogram of Form K is essentially as depicted in FIG. 6;

(iii)the DSC thermogram of Form K shows an endothermic peak in the range of 286.4°C to 290.4°C;

(iv) form K is an anhydrate.

5. The polymorph according to claim 1, wherein the XRPD pattern of the Form A comprises 3 or more diffraction peaks having 2θ selected from the group consisting of: 5.636±0.20°, 8.210±0.20°, 11.248±0.20°, 13.049±0.20°, 16.898±0.20°, 17.722±0.20°.

6. The polymorph according to claim 1, wherein the XRPD pattern of the Form A comprises 2θ diffraction peaks selected from the group consisting of: 8.684±0.20°, 14.791±0.20°, 15.592±0.20°, 17.872±0.20°, 18.721±0.20°, 21.127±0.20°, 22.543±0.20°, 24.687±0.20°, 25.757±0.20°.

7. The polymorph according to claim 1, wherein the XRPD pattern of the Form C comprises 3 or more diffraction peaks having 2θ selected from the group consisting of: 6.463±0.20°, 7.402±0.20°, 8.988±0.20°, 12.000±0.20°, 12.898±0.20°, 13.088±0.20°, 13.611±0.20°, 14.328±0.20°, 16.233±0.20°, 17.205±0.20°, 19.794±0.20°, 21.032±0.20°.

8. The polymorph according to claim 1, wherein the XRPD pattern of the Form C comprises 2θ diffraction peaks selected from the group consisting of: 10.812±0.20°, 23.376±0.20°, 24.173±0.20°, 24.815±0.20°, 26.038±0.20°, 29.921±0.20°.

9. The polymorph according to claim 1, wherein the XRPD pattern of the Form E comprises 3 or more diffraction peaks having 2θ selected from the group consisting of: 4.773±0.20°, 7.773±0.20°, 13.086±0.20°, 21.528±0.20°.

10. The polymorph according to claim 1, wherein the Form E further comprises 2θ diffraction peaks selected from the group consisting of: 16.844±0.20°, 18.108±0.20°.

11. The polymorph according to claim 1, wherein the XRPD pattern of the Form F comprises 3 or more (such as 4, 5, or 6) diffraction peaks having 2θ selected from the group consisting of: 12.132±0.20°, 12.389±0.20°, 12.809±0.20°, 15.086±0.20°, 17.853±0.20°, 18.413±0.20°, 18.627±0.20°, 22.262±0.20°, 24.325±0.20°, 25.191±0.20°.

12. The polymorph according to claim 1, wherein the XRPD pattern of the Form F further comprises 2θ diffraction peaks selected from the group consisting of: 6.310±0.20°, 13.849±0.20°, 16.717±0.20°, 17.088±0.20°, 19.179±0.20°, 19.493±0.20°, 20.259±0.20°, 23.851±0.20°, 26.158±0.20°, 28.159±0.20°, 28.556±0.20°, 34.014±0.20°.

13. The polymorph according to claim 1, wherein the XRPD pattern of the Form I comprises 3 or more (such as 4, 5, or 6) diffraction peaks having 2θ selected from the group consisting of: 5.120±0.20°, 6.627±0.20°, 12.714±0.20°, 15.388±0.20°, 18.439±0.20°, 18.978±0.20°, 25.496±0.20°.

14. The polymorph according to claim 1, wherein the XRPD pattern of the Form I further comprises 2θ diffraction peaks selected from the group consisting of: 13.197±0.20°, 14.183±0.20°, 19.535±0.20°, 22.701±0.20°, 34.482±0.20°.

15. The polymorph according to claim 1, wherein the XRPD pattern of the Form L comprises 3 or more (such as 4, 5, or 6) diffraction peaks having 2θ selected from the group consisting of: 6.586±0.20°, 8.336±0.20°, 12.065±0.20°, 12.568±0.20°, 13.569±0.20°, 14.503±0.20°, 15.950±0.20°, 17.259±0.20°, 18.918±0.20°, 23.483±0.20°.